MSKSEMI 美森科













ESD

1/5

TSS

MOV

GDT

PIFD

MMBT5401-MS

Product specification





TRANSISTOR (PNP)

FEATURES

- Complementary to MMBT5551-MS
- Ideal for Medium Power Amplification and Switching

Reference News

PACKAGE OUTLINE		MARKING
1 2	1. BASE 2. EMITTER 3.COLLECTOR	2 L
SOT-23		

MAXIMUM RATINGS (Ta=25℃ unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	-160	V
V _{CEO}	Collector-Emitter Voltage	-150	V
V _{EBO}	Emitter-Base Voltage	-5	V
l c	Collector Current	-0.6	А
Pc	Collector Power Dissipation	0.3	W
R _{。JA}	Thermal Resistance from Junction to Ambient	416	°C/W
Tj	Junction Temperature	150	°C
T _{stg}	Storage Temperature	-55~+150	℃

ELECTRICAL CHARACTERISTICS (Ta=25℃ unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	$V_{(BR)CBO}$	lc=-100μA, le=0	-160			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	Ic=-1mA, I _B =0	-150			V
Emitter-base breakdown voltage	V _{(BR)EBO}	l∈=-10μA, lc=0	-5			V
Collector cut-off current	Ісво	V _{CB} =-120V, I _E =0			-0.1	μΑ
Emitter cut-off current	IEBO	V _{EB} =-4V, I _C =0			-0.1	μA
	hFE(1)	Vce=-5V, Ic=-1mA	80			
DC current gain	hFE(2)	V _{CE} =-5V, I _C =-10mA	100		300	
	h _{FE(3)} *	Vce=-5V, Ic=-50mA	50			
Collector-emitter saturation voltage	VCE(sat)1	I _C =-10mA, I _B =-1mA			-0.2	V
	V _{CE(sat)2}	Ic=-50mA, I _B =-5mA			-0.5	V
Page emitter caturation valtage	V _{BE(sat)1}	lc=-10mA, l _B =-1mA			-1	V
Base-emitter saturation voltage	V _{BE(sat)2}	I_C =-50mA, I_B =-5mA			-1	V
Transition frequency	f_T	V _{CE} =-5V,I _C =-10mA, f=30MHz	100			MHz

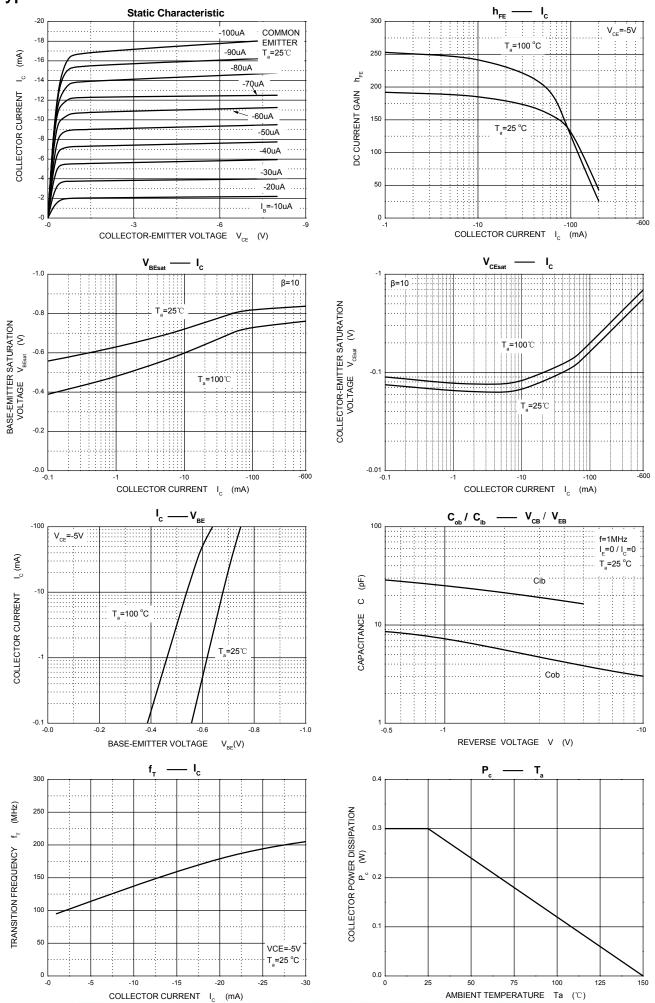
^{*}Pulse test: pulse width ≤300µs, duty cycle≤ 2.0%.

CLASSIFICATION OF hFE (2)

RANK	L	Н
RANGE	100-200	200-300

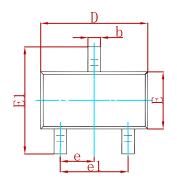


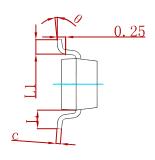
Typical Characteristics

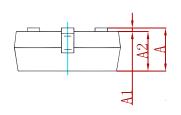




PACKAGE MECHANICAL DATA

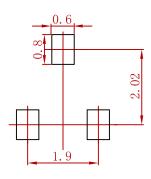






Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Зупроі	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.037	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022	REF	
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MMBT5401-MS	SOT-23	3000



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